

<b>Notice of References Cited</b>	Application/Control No. 10/715,414	Applicant(s)/Patent Under Reexamination CHAO, YUAN-JEN	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,529,914 A	07-1985	Kaneda, Isao	315/335
*	B	US-5,272,327 A	12-1993	Mitchell et al.	250/205
*	C	US-5,461,397 A	10-1995	Zhang et al.	345/102
*	D	US-5,754,159 A	05-1998	Wood et al.	345/102
*	E	US-5,818,172 A	10-1998	Lee, Chang-Hum	315/86
*	F	US-5,854,617 A	12-1998	Lee et al.	345/102
*	G	US-5,892,336 A	04-1999	Lin et al.	315/291
*	H	US-6,060,843 A	05-2000	Primisser et al.	315/291
*	I	US-6,069,449 A	05-2000	Murakami, Isao	315/158
*	J	US-6,075,325 A	06-2000	Kouno et al.	315/307
*	K	US-6,104,146 A	08-2000	Chou et al.	315/277
*	L	US-6,201,352 B1	03-2001	Ge et al.	315/169.1
*	M	US-6,243,067 B1	06-2001	Noguchi et al.	345/102

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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	U	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,243,068 B1	06-2001	Evanicky et al.	345/102
*	B	US-6,420,839 B1	07-2002	Chiang et al.	315/311
*	C	US-6,448,955 B1	09-2002	Evanicky et al.	345/102
*	D	US-2002/0140538 A1	10-2002	Yer et al.	336/198
*	E	US-6,496,236 B1	12-2002	Cole et al.	349/61
*	F	US-2003/0122771 A1	07-2003	Sumiyoshi et al.	345/102
*	G	US-6,856,519 B2	02-2005	Lin et al.	363/16
*	H	US-2005/0057486 A1	03-2005	Aoki et al.	345/102
*	I	US-6,947,024 B2	09-2005	Lee et al.	345/102
*	J	US-6,961,044 B2	11-2005	Woo, Jong Hyun	345/102
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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